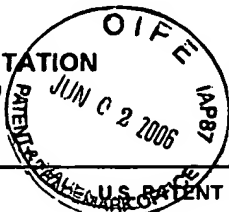


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| INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i> | | | | ATTY DOCKET NO. <div style="text-align: center;">200-0665</div> | | APPLICATION NO. <div style="text-align: center;">09/965,904</div> | |
| | | | | APPLICANT(S) <div style="text-align: center;">Joseph G. Walacavage et al.</div> | | | |

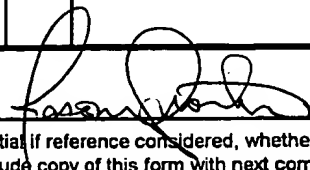


| U.S. PATENT DOCUMENTS | | | | | | | |
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| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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| U.S. PATENT APPLICATION PUBLICATIONS | | | | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | | |
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| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
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| OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i> | | | |
|---|--|--|--|
| T30 | | | S. Kanai, T. Kishinami, "A Virtual Verification Environment for the Sequence Control System Using VRML and JAVA," 1999 by ASME, pages 1-8. |
| T30 | | | "ThermaView Advanced Welder Diagnostics System," 1998. |
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| EXAMINER  | DATE CONSIDERED <div style="text-align: center; font-size: 1.2em;">8/14/2006</div> |
|---|---|

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.